

Search Notes

Application/Control No.

10/786,158

Examiner

Alvin C. Chin-Shue

Applicant(s)/Patent under
Reexamination

BEAN ET AL.

Art Unit

3634

SEARCHED

Class	Subclass	Date	Examiner
182	18	10.6.06	AC
	19		
	2.8-		
	2.11		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR